

Automated software-based in-field self-test program synthesis

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Automated software-based self-test generation for microprocessors

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High-level modeling and testing of multiple control faults in digital systems

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High-level test data generation for software based self-test in microprocessors

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In-system programming of non-volatile memories on microprocessor-centric boards

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On in-system programming of non-volatile memories

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Software-based self-test with decision diagrams for microprocessors

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